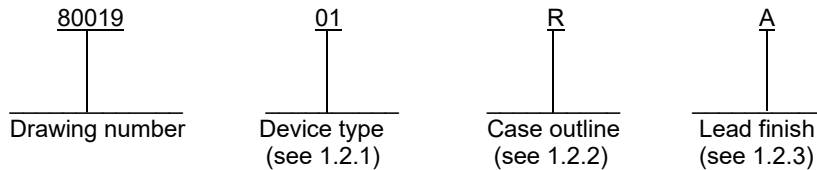


1. SCOPE

1.1 Scope. This drawing describes device requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A.

1.2 Part or Identifying Number (PIN). The complete PIN is as shown in the following example:



1.2.1 Device types. The device types identify the circuit function as follows:

| <u>Device type</u> | <u>Generic number</u> | <u>Circuit function</u> |
|--------------------|-----------------------|---|
| 01 | 54LS09 | Quad, 2-input AND gate with open collector output |

1.2.2 Case outline. The case outline are as designated in MIL-STD-1835 and as follows:

| <u>Outline letter</u> | <u>Descriptive designator</u> | <u>Terminals</u> | <u>Package style</u> |
|-----------------------|-------------------------------|------------------|----------------------|
| C | GDIP1-T14 or CDIP2-T14 | 14 | dual-in-line |
| D | GDFP1-F14 or CDFP2-F14 | 14 | flat |
| 2 | CQCC1-N20 | 20 | square chip carrier |

1.2.3 Lead finish. The lead finish is as specified in MIL-PRF-38535, appendix A.

1.3 Absolute maximum ratings.

| | |
|---|---------------------------------|
| Supply voltage | -0.5 V dc to +7.0 V dc |
| Input voltage range | -1.5 V dc at -18 mA to 5.5 V dc |
| Storage temperature range | -65°C to +150°C |
| Maximum power dissipation (P _D) | 48.4 mW |
| Lead temperature (soldering, 10 seconds) | +300°C |
| Thermal resistance, junction-to-case (θ _{JC}) | See MIL-STD-1835 |
| Junction temperature (T _J) | +175°C |

1.4 Recommended operating conditions.

| | |
|---|--------------------------------------|
| Supply voltage range (V _{CC}) | 4.5 V dc minimum to 5.5 V dc maximum |
| Minimum high level input voltage (V _{IH}) | 2.0 V dc |
| Maximum low level input voltage (V _{IL}) | 0.7 V dc |
| Case operating temperature range (T _C) | -55°C to +125°C |
| High level output voltage (V _{OH}) | 5.5 V maximum |

| | | | |
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| STANDARD MICROCIRCUIT DRAWING DLA LAND AND MARITIME COLUMBUS, OHIO 43218-3990 | SIZE A | | 80019 |
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2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard Microcircuits.
MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings.
MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at <https://quicksearch.dla.mil/>.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein. Product built to this drawing that is produced by a Qualified Manufacturer Listing (QML) certified and qualified manufacturer or a manufacturer who has been granted transitional certification to MIL-PRF-38535 may be processed as QML product in accordance with the manufacturers approved program plan and qualifying activity approval in accordance with MIL-PRF-38535. This QML flow as documented in the Quality Management (QM) plan may make modifications to the requirements herein. These modifications shall not affect form, fit, or function of the device. These modifications shall not affect the PIN as described herein. A "Q" or "QML" certification mark in accordance with MIL-PRF-38535 is required to identify when the QML flow option is used.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535, appendix A and herein.

3.2.1 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.3 Truth tables. The truth tables shall be as specified on figure 2.

3.2.4 Logic diagrams. The logic diagrams shall be as specified on figure 3.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full case operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-PRF-38535, appendix A. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked.

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3.5.1 Certification/compliance mark. A compliance indicator "C" shall be marked on all non-JAN devices built in compliance to MIL-PRF-38535, appendix A. The compliance indicator "C" shall be replaced with a "Q" or "QML" certification mark in accordance with MIL-PRF-38535 to identify when the QML flow option is used.

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6 herein). The certificate of compliance submitted to DLA Land and Maritime-VA prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-PRF-38535, appendix A and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DLA Land and Maritime-VA shall be required for any change that affects this drawing.

3.9 Verification and review. DLA Land and Maritime, DLA Land and Maritime's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

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TABLE I. Electrical performance characteristics.

| Test | Symbol | Conditions -55°C ≤ T _C ≤ +125°C unless otherwise specified | Group A subgroups | Device type | Limits | | Unit |
|--------------------------------------|-------------------|---|----------------------|----------------|--------|------|------|
| | | | | | Min | Max | |
| Low level output voltage | V _{OL} | V _{CC} = 4.5 V, I _{OL} = 4 mA V _{IN} = 0.7 V or 2.0 V, | 1, 2, 3 | All | | 0.4 | V |
| Input clamp voltage | V _{IC} | V _{CC} = 4.5 V, I _{IN} = -18 mA, T _C = +25°C | 1 | All | | -1.5 | V |
| High level input current | I _{IH1} | V _{CC} = 5.5 V, V _{IN} = 2.7 V | 1, 2, 3 | All | | 50 | μA |
| | I _{IH2} | V _{CC} = 5.5 V, V _{IN} = 5.5 V | 1, 2, 3 | All | | 0.1 | mA |
| Low level input current | I _{IL} | V _{CC} = 5.5 V, V _{IN} = 0.4 V | 1, 2, 3 | All | | -0.4 | mA |
| Maximum collector cut-off Current | I _{CEX} | V _{CC} = 5.5 V, V _{IH} = 2.0 V, V _{OH} = 5.5 V | 1, 2, 3 | All | | 0.1 | mA |
| High level supply current | I _{CCCH} | V _{CC} = 5.5 V, V _{IN} = 4.5 V | 1, 2, 3 | All | | 4.8 | mA |
| Low level supply current | I _{CCCL} | V _{CC} = 5.5 V, V _{IN} = 0.0 V | 1, 2, 3 | All | | 8.8 | mA |
| Functional tests | | See 4.3.1c | 7 | All | | | |
| Propagation delay time, A, B to Y | t _{PHL} | V _{CC} = 5.0 V, C _L = 50 pF ±10%, R _L = 2 kΩ ±5% | 9, 10, 11 | All | | 53 | ns |
| | t _{PLH} | | 9, 10, 11 | All | | 53 | ns |

1/ Propagation delay time testing may be performed using either C_L = 15 pF or C_L = 50 pF. However, the manufacturer must certify and guarantee that the microcircuits meet the switching test limits specified for a 50 pF load.

2/ Propagation delay limits are based on single output switching. The load circuit shall consist of the specified R_L and C_L in series, with R_L tied to V_{CC} and C_L tied to GND. The device test point shall be the node between C_L and R_L. t_{PHL} and t_{PLH} voltage waveforms shall be in accordance with method 3003 of MIL-STD-883, with threshold voltage points at 50 percent; t_r ≤ 15 ns, t_f ≤ 6 ns.

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| | | |
|-----------------|------------------|-----------------|
| Device types | 01 | 01 |
| Case outlines | C, D | 2 |
| Terminal number | Terminal symbols | |
| 1 | 1A | NC |
| 2 | 1B | 1A |
| 3 | 1Y | 1B |
| 4 | 2A | 1Y |
| 5 | 2B | NC |
| 6 | 2Y | 2A |
| 7 | GND | NC |
| 8 | 3Y | 2B |
| 9 | 3A | 2Y |
| 10 | 3B | GND |
| 11 | 4Y | NC |
| 12 | 4A | 3Y |
| 13 | 4B | 3A |
| 14 | V _{CC} | 3B |
| 15 | --- | NC |
| 16 | --- | 4Y |
| 17 | --- | NC |
| 18 | --- | 4A |
| 19 | --- | 4B |
| 20 | --- | V _{CC} |

FIGURE 1. Terminal connections.

| Inputs | | Output |
|--------|---|--------|
| A | B | Y |
| L | L | L |
| H | L | L |
| L | H | L |
| H | H | H |

Positive logic $Y = AB$
H = High level voltage
L = Low level voltage

FIGURE 2. Truth table.

| | | | |
|--|-------------------|-----------------------------|----------------|
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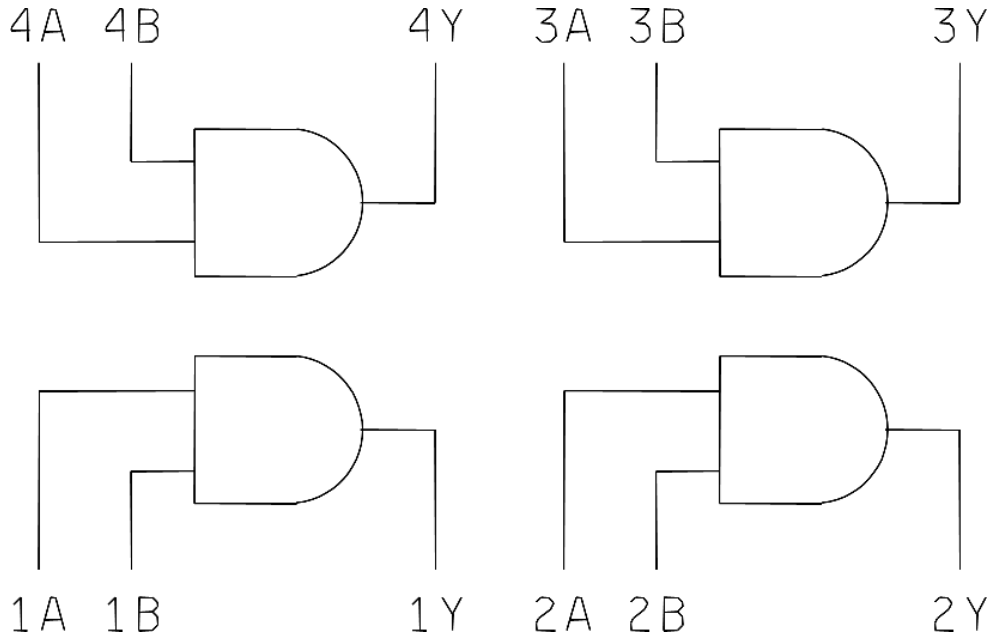


FIGURE 3. Logic diagram.

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MICROCIRCUIT DRAWING**
DLA LAND AND MARITIME
COLUMBUS, OHIO 43218-3990

SIZE
A

80019

REVISION LEVEL
J

SHEET **7**

4. VERIFICATION

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, or C or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.
 - (2) $T_A = +125^{\circ}\text{C}$, minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

TABLE II. Electrical test requirements.

| MIL-STD-883 test requirement | Subgroups (in accordance with MIL-STD-883, method 5005, table I) |
|---|---|
| Interim electrical parameters method 5004) | --- |
| Final electrical test parameters (method 5004) | 1*, 2, 3, 9 |
| Group A test requirements (method 5005) | 1, 2, 3, 7,9, 10**, 11** |
| Group C and D end-point electrical parameters (method 5005) | 1, 2, 3 |

* PDA applies to subgroup 1.
 ** Subgroups 10 and 11, if not tested, shall be guaranteed to the specified limits in table I.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, 6 and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroups 7 and 8 shall include verification of the truth table.

| | | | |
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4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.
 - (2) $T_A = +125^{\circ}\text{C}$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535, appendix A.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal, or email communication.

6.4 Record of users. Military and industrial users shall inform DLA Land and Maritime when a system application requires configuration control and the applicable SMD to that system. DLA Land and Maritime will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DLA Land and Maritime-VA, telephone (614) 692-8108.

6.5 Comments. Comments on this drawing should be directed to DLA Land and Maritime-VA, Columbus, Ohio 43218-3990, or telephone (614) 692-0591.

6.6 Approved sources of supply. Approved sources of supply are listed in MIL-HDBK-103 and QML-38535. The vendors listed in MIL-HDBK-103 and QML-38535 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DLA Land and Maritime-VA.

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STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 22-04-04

Approved sources of supply for SMD 80019 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DLA Land and Maritime-VA. This information bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535. DLA Land and Maritime maintains an online database of all current sources of supply at <https://landandmaritimeapps.dla.mil/programs/smcr/>.

| Standard microcircuit drawing PIN <u>1/</u> | Vendor CAGE number | Vendor similar PIN <u>2/</u> | Reference military specification PIN |
|--|--------------------------------------|---|---|
| 8001901CA | 01295 58625 <u>3/</u> 0C7V7 | SNJ54LS09J SL54LS09/BCA 54LS09/BCAJC QP54LS09/BCA | M38510/31005BCA |
| 8001901DA | 01295 58625 <u>3/</u> 0C7V7 | SNJ54LS09W SL54LS09/BDA 54LS09/BDAJC QP54LS09/BDA | M38510/31005BDA |
| 80019012A | 01295 58625 <u>3/</u> 0C7V7 | SNJ54LS09FK SL54LS09/B2A 54LS09/B2AJC QP54LS09/B2A | M38510/31005B2A |
| 80019012C | 58625 0C7V7 | SL54LS09/B2C QP54LS09/B2C | M38510/31005B2C |

1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.

2/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

3/ Not available from approved source of supply.

Vendor CAGE
number

Vendor name
and address

01295

Texas Instruments, Inc.
Semiconductor Group
8505 Forest Ln.
P.O. Box 660199
Dallas, TX 75243

58625

Lansdale Semiconductor Inc.
5245 S. 39th St.
Phoenix AZ 85040-9008

0C7V7

Teledyne e2v, Inc.
765 Sycamore Drive
Milpitas, CA 95035

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